

# DC Input 4-Pin Phototransistor Optocoupler

#### **Features**

- High isolation 5000 VRMS
- CTR flexibility available see order information
- DC input with transistor output
- External Creepage ≥ 7.5mm (S/SL Type)
- External Creepage ≥ 8.0mm (SLM Type)
- Operating Temperature range 55 ℃ to 110 ℃
- Regulatory Approvals
  - UL UL1577 (E364000)
  - VDE EN60747-5-5(VDE0884-5)
  - CQC GB4943.1, GB8898
  - IEC60065, IEC60950

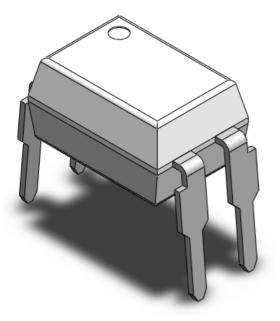
### **Description**

The CT816 series consists of a photo transistor optically coupled to a gallium arsenide Infrared-emitting diode in a 4-lead DIP package with bending options.

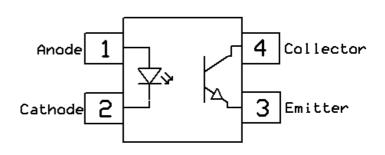
## **Applications**

- Switch mode power supplies
- Computer peripheral interface
- Microprocessor system interface

## **Package Outline**



#### **Schematic**





# **DC Input 4-Pin Phototransistor Optocoupler**

## Absolute Maximum Rating at 25°C

Symbol	Parameters	Ratings	Units	Notes
Viso	Isolation voltage (AC, 1 minute)	5000	V <sub>RMS</sub>	
Ртот	Total power dissipation	200	mW	
Topr	Operating temperature	-55 ~ +110	°C	
Tstg	Storage temperature	-55 ~ +150	°C	
Tsol	Soldering temperature	260	°C	
Emitter				
l <sub>F</sub>	Forward current	60	mA	
I <sub>F(TRANS)</sub>	Peak transient current (≤1µs P.W,300pps)	1	Α	
V <sub>R</sub>	Reverse voltage	6	V	
P <sub>D</sub>	Emitter power dissipation	100	mW	
Detector	•			
PD	Detector power dissipation	150	mW	
Bvceo	Collector-Emitter Breakdown Voltage	80	V	
Bveco	Emitter-Collector Breakdown Voltage	6	V	
Ic	Collector Current	50	mA	



# **DC Input 4-Pin Phototransistor Optocoupler**

# **Electrical Characteristics** $T_A = 25 \, ^{\circ}\text{C}$ (unless otherwise specified)

#### **Emitter Characteristics**

Symbol	Parameters	Test Conditions	Min	Тур	Max	Units	Notes
VF	Forward voltage	I <sub>F</sub> =10mA		1.24	1.4	٧	
I <sub>R</sub>	Reverse Current	V <sub>R</sub> = 6V	-	-	5	μΑ	
C <sub>IN</sub>	Input Capacitance	f= 1MHz	-	30	-	pF	

#### **Detector Characteristics**

Symbol	Parameters	Test Conditions	Min	Тур	Max	Units	Notes
Bvceo	Collector-Emitter Breakdown	I <sub>C</sub> = 100μA	80	-	-	٧	
Bveco	Emitter-Collector Breakdown	I <sub>E</sub> = 100μA	6	-	-	٧	
Iceo	Collector-Emitter Dark Current	V <sub>CE</sub> = 20V, I <sub>F</sub> =0mA	-	-	100	nA	

#### **Transfer Characteristics**

Symbol	Parameters		Test Conditions	Min	Тур	Max	Units	Notes
	CTR   Current Transfer Ratio   CT816A   CT816B   CT816C   CT816D   CT816F   CT816F	CT816		50	-	600	- %	
		CT816A		80	-	160		
OTD		CT816B		130	-	260		
CIR		CT816C	IF= SITIA, VCE= SV	200	-	400		
			300	-	600	-		
		CT816F		100	-	200		
		CT816I	I <sub>F</sub> = 10mA, V <sub>CE</sub> = 5V	63	-	125	- %	
		CT816J		100	-	200		
OTD	Command Transfer Datie	CT816K		160	-	320		
CTR	Current Transfer Ratio	CT816I		22	-	-	%	
		CT816J	I <sub>F</sub> = 1mA, V <sub>CE</sub> = 5V	34	-	-		
		CT816K		56	-	-		
V	Collector-Emitter Satura	ation	00mA   1mA		0.1	0.0	V	
V <sub>CE(SAT)</sub>	Voltage		I <sub>F</sub> = 20mA, I <sub>C</sub> = 1mA	-	0.1	0.2	V	
Rio	Isolation Resistance		V <sub>IO</sub> = 500V <sub>DC</sub>	5x10 <sup>10</sup>	-	-	Ω	
Сю	Isolation Capacitance		f= 1MHz	-	0.25	1	pF	

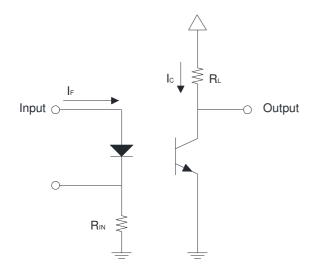


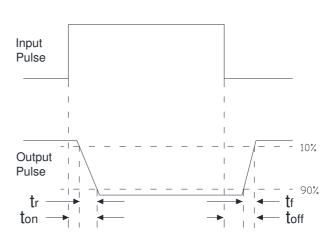
# **DC Input 4-Pin Phototransistor Optocoupler**

## **Switching Characteristics**

Symbol	Parameters	Test Conditions	Min	Тур	Max	Units	Notes
tr	Rise Time	I <sub>C</sub> = 2mA, V <sub>CE</sub> = 2V, R <sub>L</sub> = 100Ω	-	6	-		
tf	Fall Time	IC= 2111A, VCE= 2V, NE= 10032	-	8	-	μS	

## **Test Circuit**

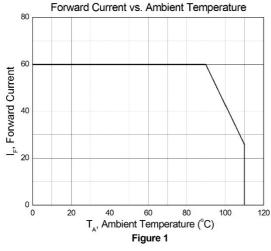


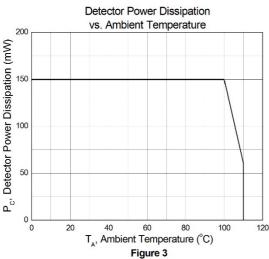


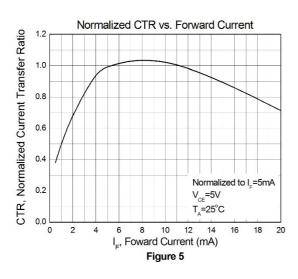


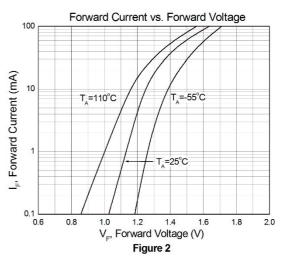


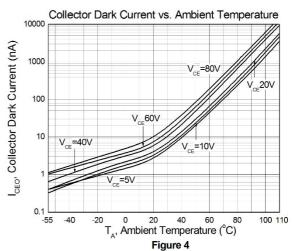
# **Typical Characteristic Curves**

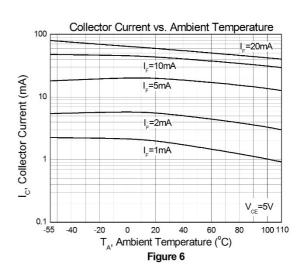






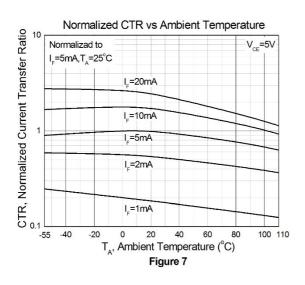


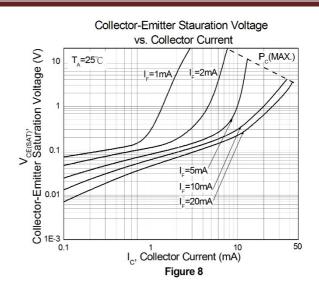


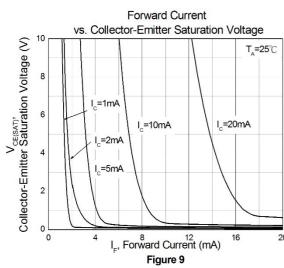


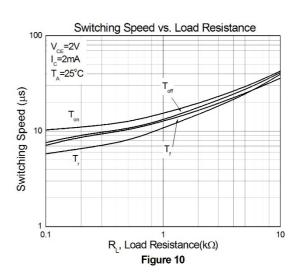


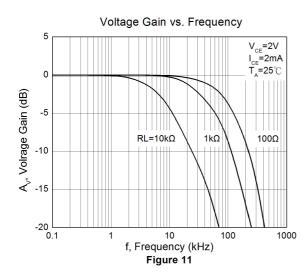
# DC Input 4-Pin Phototransistor Optocoupler











Rev 3

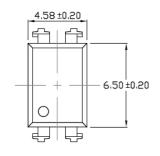
May, 2016

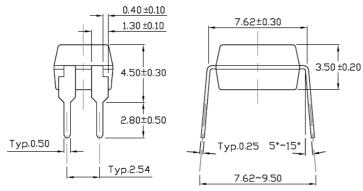


# DC Input 4-Pin Phototransistor Optocoupler

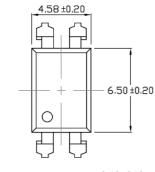
## Package Dimension Dimensions in mm unless otherwise stated

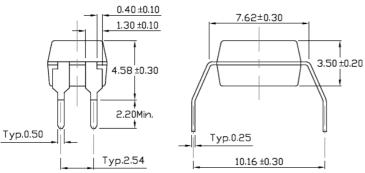
#### Standard DIP - Through Hole





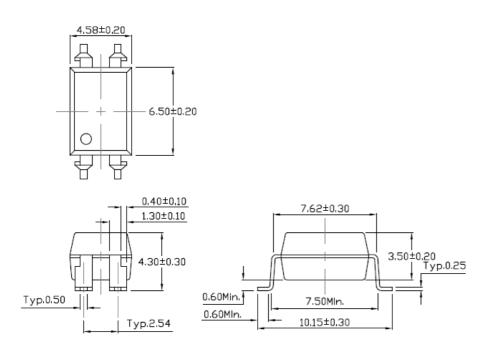
## Gullwing (400mil) Lead Forming – Through Hole (M Type)



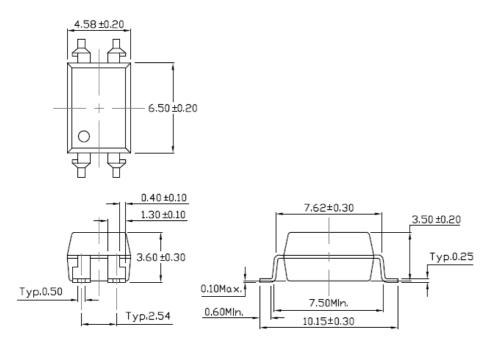




## **Surface Mount Lead Forming (S Type)**



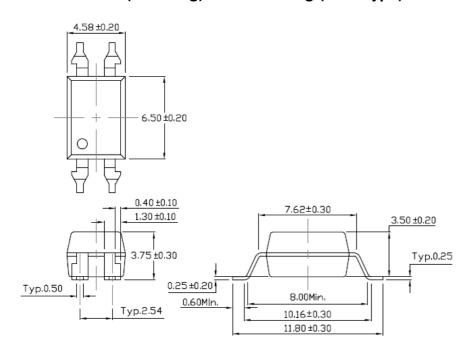
### Surface Mount (Low Profile) Lead Forming (SL Type)







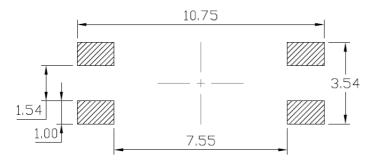
## **Surface Mount (Gullwing) Lead Forming (SLM Type)**



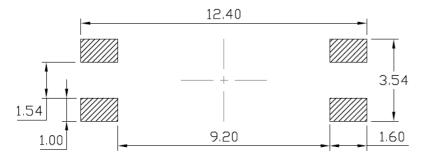


#### Recommended Solder Mask Dimensions in mm unless otherwise stated

#### Surface Mount Lead Forming & Surface Mount (Low Profile) Lead Forming



#### **Surface Mount (Gullwing) Lead Forming**



## **Marking Information**



#### Note:

CT : Denotes "CT Micro"

816 : Part NumberV : VDE OptionR : CTR RankY : Fiscal YearWW : Work Week

K : Manufacturing Code





## **Ordering Information**

CT816X(V)(Y)(Z)-HG

X = Part No. (X=A, B, C, D, I, J, K, None)

V = VDE Option (V or None)

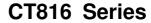
Y = Lead form option (S, SL, M, SLM or none)

Z = Tape and reel option (T1, T2, T3, T4 or none)

H = Lead frame option (H: Iron, None: Copper)

G= Material option (G: Green, None: Non-green)

Option	Description	Quantity
None	Standard 4 Pin DIP	100 Units/Tube
М	Gullwing (400mil) Lead Forming	100 Units/Tube
S(T1)	Surface Mount Lead Forming – With Option 1 Taping	1500 Units/Reel
S(T2)	Surface Mount Lead Forming – With Option 2 Taping	1500 Units/Reel
S(T3)	Surface Mount Lead Forming – With Option 3 Taping	1000 Units/Reel
S(T4)	Surface Mount Lead Forming – With Option 4 Taping	1000 Units/Reel
SL(T1)	Surface Mount (Low Profile) Lead Forming- With Option 1 Taping	1500 Units/Reel
SL(T2)	Surface Mount (Low Profile) Lead Forming – With Option 2 Taping	1500 Units/Reel
SL(T3)	Surface Mount (Low Profile) Lead Forming- With Option 3 Taping	1000 Units/Reel
SL(T4)	Surface Mount (Low Profile) Lead Forming – With Option 4 Taping	1000 Units/Reel
SLM(T1)	Surface Mount (Gullwing) Lead Forming- With Option 1 Taping	1500 Units/Reel
SLM(T2)	Surface Mount (Gullwing) Lead Forming – With Option 2 Taping	1500 Units/Reel

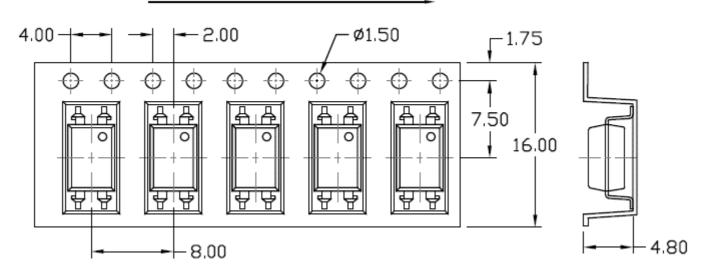




## Carrier Tape Specifications Dimensions in mm unless otherwise stated

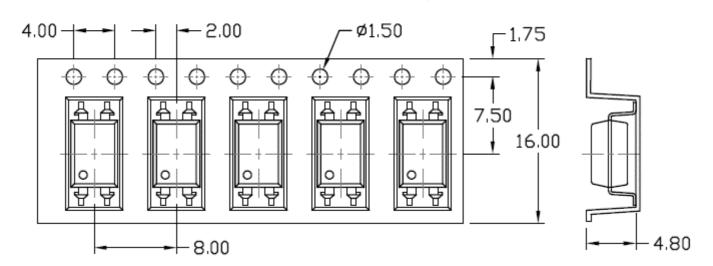
## Option S(T1) & SL(T1)

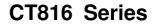
# Input Direction



## Option S(T2) & SL(T2)

# Input Direction

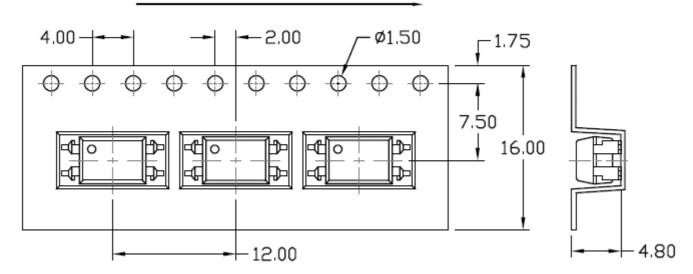






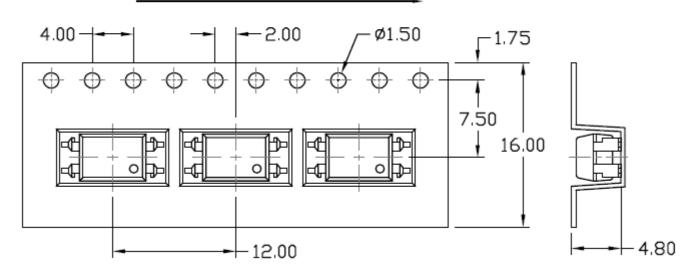
## Option S(T3) & SL(T3)

# Input Direction



## Option S(T4) & SL(T4)

# Input Direction

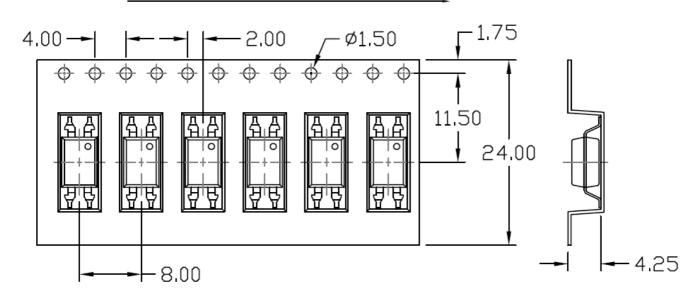






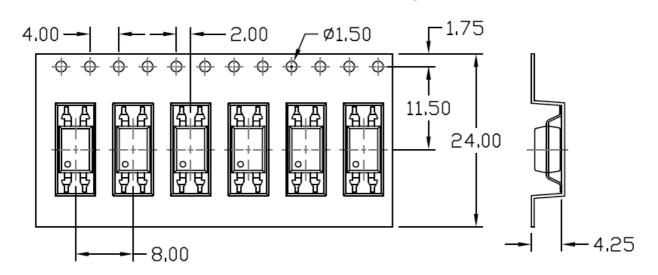
## **Option SLM(T1)**

# Input Direction



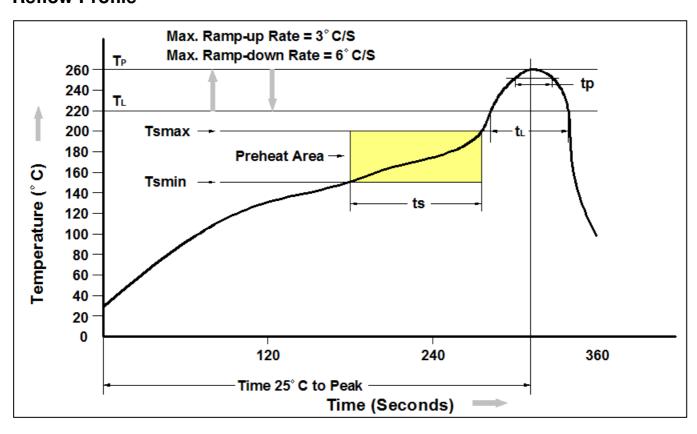
### **Option SLM(T2)**

# Input Direction





#### **Reflow Profile**



Profile Feature	Pb-Free Assembly Profile
Temperature Min. (Tsmin)	150℃
Temperature Max. (Tsmax)	200℃
Time (ts) from (Tsmin to Tsmax)	60-120 seconds
Ramp-up Rate (t <sub>L</sub> to t <sub>P</sub> )	3℃/second max.
Liquidous Temperature (T <sub>L</sub> )	217℃
Time (t <sub>L</sub> ) Maintained Above (T <sub>L</sub> )	60 – 150 seconds
Peak Body Package Temperature	260℃ +0℃ / -5℃
Time (t <sub>P</sub> ) within 5℃ of 260℃	30 seconds
Ramp-down Rate (T <sub>P</sub> to T <sub>L</sub> )	6°C/second max
Time 25℃ to Peak Temperature	8 minutes max.



# DC Input 4-Pin Phototransistor Optocoupler

#### **DISCLAIMER**

CT MICRO RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION OR DESIGN. CT MICRO DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS.

DISCOLORATION MIGHT OCCUR ON THE PACKAGE SURFACE AFTER SOLDERING, REFLOW OR LONG TERM USE. THIS DOES NOT IMPACT THE PRODUCT PERFORMANCE NOR THE PRODUCT RELIABILITY.

CT MICRO ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT EXPRESS WRITTEN APPROVAL OF CT MICRO INTERNATIONAL CORPORATION.

- Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, or (c) whose failure to perform when properly used in accordance with instruction for use provided in the labelling, can be reasonably expected to result in significant injury to the user.
- A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.